

<b>Notice of References Cited</b>	Application/Control No. 10/567,117	Applicant(s)/Patent Under Reexamination FUJIWARA ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0202954 A1	10-2004	Momota et al.	430/170
*	B	US-2004/0176630 A1	09-2004	Watanabe et al.	558/430
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
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**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
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**NON-PATENT DOCUMENTS**

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